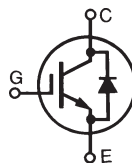


**High Voltage, High Gain  
BiMOSFET™**
**IXBK64N250  
IXBX64N250**

$$V_{CES} = 2500 \text{ V}$$

$$I_{C25} = 75 \text{ A}$$

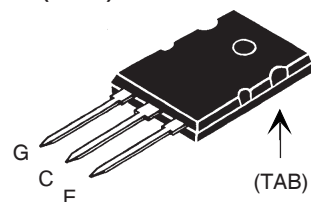
$$V_{CE(sat)} \leq 3.0 \text{ V}$$

**Monolithic Bipolar MOS Transistor**


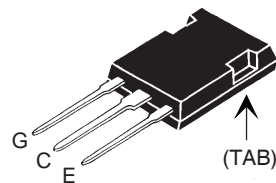
Symbol	Test Conditions	Maximum Ratings	
$V_{CES}$	$T_J = 25^\circ\text{C to } 150^\circ\text{C}$	2500	V
$V_{GES}$	Continuous	$\pm 25$	V
$V_{GEM}$	Transient	$\pm 35$	V
$I_{C25}$	$T_C = 25^\circ\text{C}$ , Lead RMS limit	75	A
$I_{C110}$	$T_C = 110^\circ\text{C}$	64	A
$I_{CM}$	$T_C = 25^\circ\text{C}$ , 1ms	600	A
<b>SSOA (RBSOA)</b>	$V_{GE} = 15\text{V}$ , $T_{VJ} = 125^\circ\text{C}$ , $R_G = 3\Omega$ Clamped inductive load	$I_{CM} = 160$ $V_{CES} = 2000$	A V
<b><math>T_{SC}</math> (SCSOA)</b>	$V_{GE} = 15\text{V}$ , $T_J = 125^\circ\text{C}$ , $R_G = 5\Omega$ , $V_{CE} = 1250\text{V}$ , non-repetitive	10	$\mu\text{s}$
$P_C$	$T_C = 25^\circ\text{C}$	735	W
$T_J$		-55 ... +150	$^\circ\text{C}$
$T_{JM}$		150	$^\circ\text{C}$
$T_{stg}$		-55 ... +150	$^\circ\text{C}$
$T_L$	1.6mm (0.063 in.) from case for 10s	300	$^\circ\text{C}$
$T_{SOLD}$	Plastic body for 10s	260	$^\circ\text{C}$
$F_C$	Mounting force (PLUS247™)	20...120/4.5...27	N/lb.
$M_d$	Mounting torque (TO264)	1.13/10	Nm/lb.in.
<b>Weight</b>	(PLUS247™)	6	g
	(TO-264)	10	g

Symbol	Test Conditions	Characteristic Values ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)		
		Min.	Typ.	Max.
$BV_{CES}$	$I_C = 1\text{mA}$ , $V_{GE} = 0\text{V}$	2500		V
$V_{GE(th)}$	$I_C = 4\text{mA}$ , $V_{CE} = V_{GE}$	3.0		5.0 V
$I_{CES}$	$V_{CE} = 0.8V_{CES}$ $V_{GE} = 0\text{V}$	$T_J = 25^\circ\text{C}$		50 $\mu\text{A}$
		$T_J = 125^\circ\text{C}$		6 mA
$I_{GES}$	$V_{CE} = 0\text{V}$ , $V_{GE} = \pm 25\text{V}$			$\pm 200$ nA
$V_{CE(sat)}$	$I_C = I_{C110}$ , $V_{GE} = 15\text{V}$	$T_J = 125^\circ\text{C}$	2.5	3.0 V
			3.1	V

TO-264 (IXBK)



PLUS247™ (IXBX)



G = Gate, C = Collector,  
E = Emitter, TAB = Collector

**Features**

- High Blocking Voltage
- International standard package
- Low conduction losses
- High current handling capability
- MOS Gate turn-on - drive simplicity

**Applications**

- Uninterruptible power supplies (UPS)
- Switched-mode and resonant-mode power supplies
- Capacitor discharge circuits
- Laser Generators

**Advantages**

- Easy to mount
- Space Savings
- High power density

Symbol	Test Conditions	Characteristic Values ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)		
		Min.	Typ.	Max.
$g_{fs}$	$I_C = 64\text{A}$ , $V_{CE} = 10\text{V}$ , Pulse test, $t \leq 300\mu\text{s}$ , duty cycle $\leq 2\%$	40	72	S
$C_{ies}$	$V_{CE} = 25\text{V}$ , $V_{GE} = 0\text{V}$ , $f = 1\text{MHz}$		10400	pF
$C_{oes}$			360	pF
$C_{res}$			120	pF
$Q_g$	$I_C = 64\text{A}$ , $V_{GE} = 15\text{V}$ , $V_{CE} = 0.5 V_{CES}$		400	nC
$Q_{ge}$			46	nC
$Q_{gc}$			155	nC
$t_{d(on)}$	<b>Resistive load, <math>T_J = 25^\circ\text{C}</math></b>		49	ns
$t_{ri}$			318	ns
$t_{d(off)}$	$I_C = 128\text{A}$ , $V_{GE} = 15\text{V}$ $V_{CE} = 1250\text{V}$ , $R_G = 1\Omega$		232	ns
$t_{fi}$			170	ns
$t_{d(on)}$	<b>Resistive load, <math>T_J = 125^\circ\text{C}</math></b>		54	ns
$t_{ri}$			578	ns
$t_{d(off)}$	$I_C = 128\text{A}$ , $V_{GE} = 15\text{V}$ $V_{CE} = 1250\text{V}$ , $R_G = 1\Omega$		222	ns
$t_{fi}$			175	ns
$R_{thJC}$				$0.17^\circ\text{C/W}$
$R_{thCS}$		0.15		$^\circ\text{C/W}$

Symbol	Test Conditions	Characteristic Values ( $T_J = 25^\circ\text{C}$ , unless otherwise specified)		
		Min.	Typ.	Max.
$V_F$	$I_F = 64\text{A}$ , $V_{GE} = 0\text{V}$ , Pulse test, $t \leq 300\mu\text{s}$ , duty cycle, $d \leq 2\%$			3.0 V
$I_{RM}$	$I_F = 64\text{A}$ , $V_{GE} = 0\text{V}$ , $-di_F/dt = 650\text{A}/\mu\text{s}$		160	A
$t_{rr}$			480	ns

Note:  
Additional provisions for lead-to-lead isolation are required at  $V_{CE} > 1200\text{V}$ .

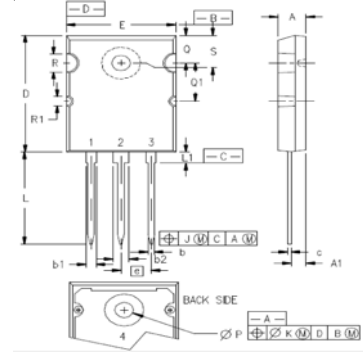
### PRELIMINARY TECHNICAL INFORMATION

The product presented herein is under development. The Technical Specifications offered are derived from data gathered during objective characterizations of preliminary engineering lots; but also may yet contain some information supplied during a pre-production design evaluation. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered	4,835,592	4,931,844	5,049,961	5,237,481	6,162,665	6,404,065 B1	6,683,344	6,727,585	7,005,734 B2	7,157,338 B2
by one or more of the following U.S. patents:	4,850,072	5,017,508	5,063,307	5,381,025	6,259,123 B1	6,534,343	6,710,405 B2	6,759,692	7,063,975 B2	
	4,881,106	5,034,796	5,187,117	5,486,715	6,306,728 B1	6,583,505	6,710,463	6,771,478 B2	7,071,537	

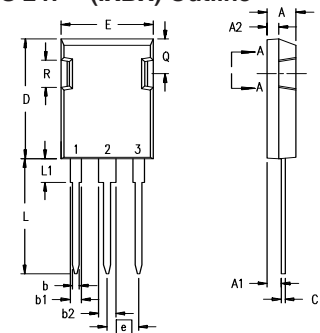
### TO-264 (IXBK) Outline



- 1 - GATE
- 2, 4 - DRAIN (COLLECTOR)
- 3 - SOURCE (EMITTER)

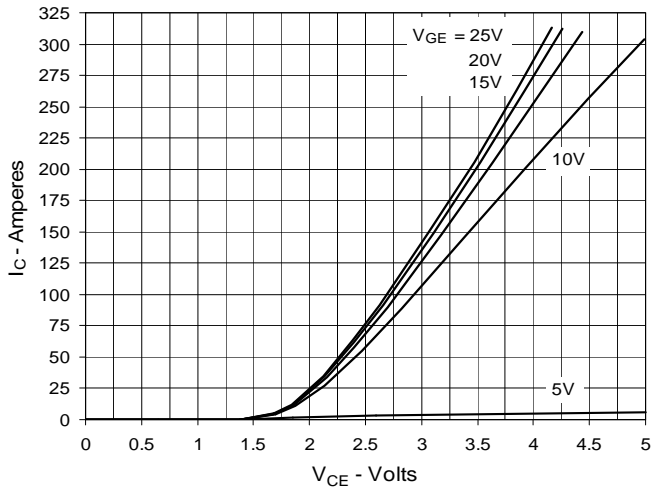
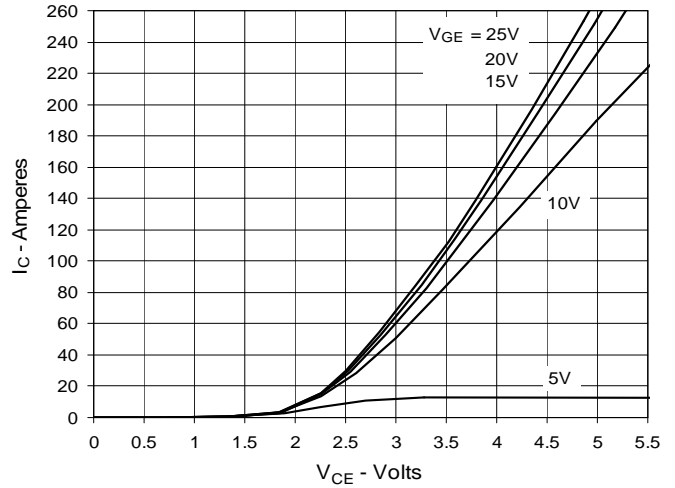
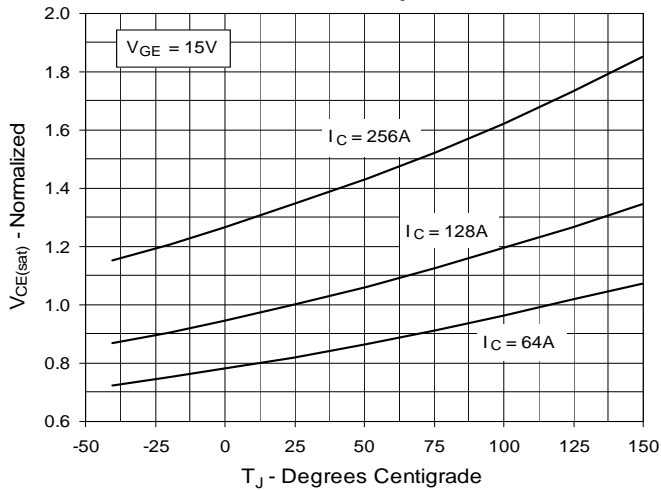
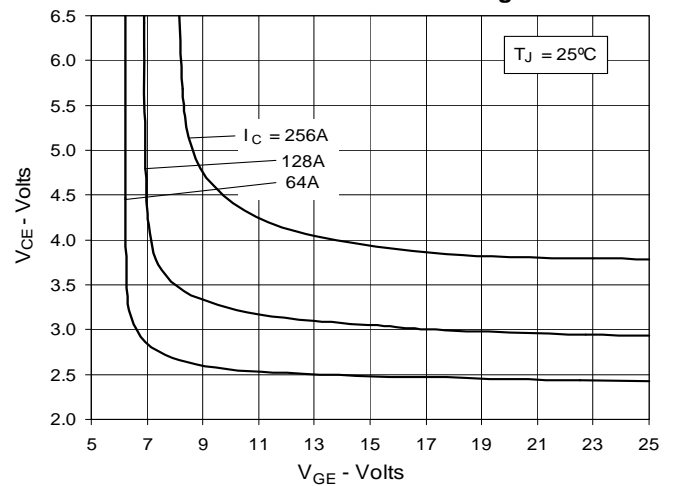
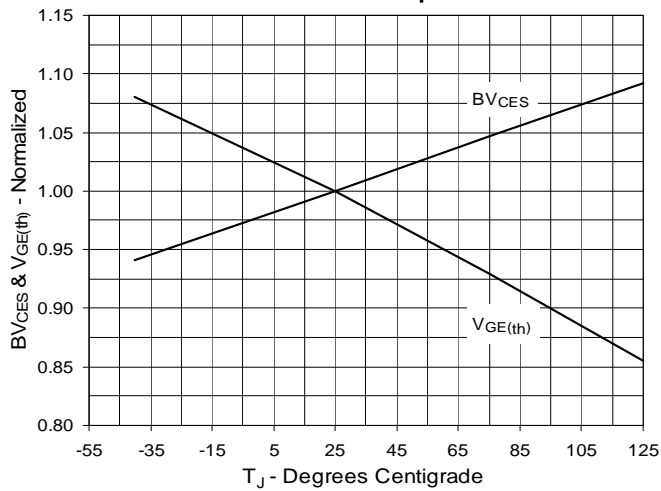
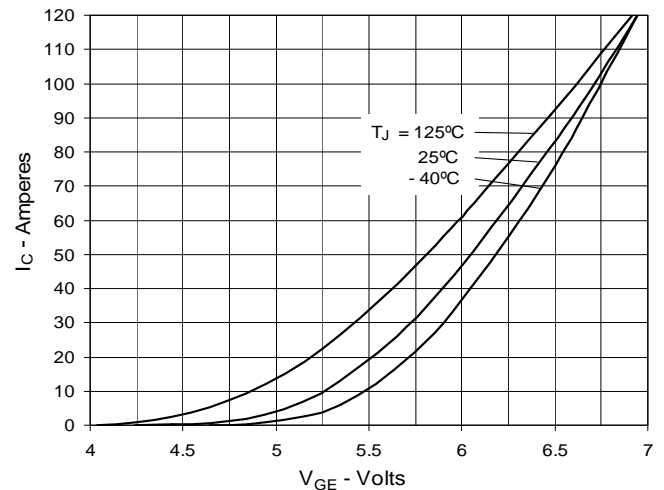
SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.185	.209	4.70	5.31
A1	.102	.118	2.59	3.00
b	.037	.055	0.94	1.40
b1	.087	.102	2.21	2.59
b2	.110	.126	2.79	3.20
c	.017	.029	0.43	0.74
D	1.007	1.047	25.58	26.59
E	.760	.799	19.30	20.29
e	.215 BSC		5.46 BSC	
J	.000	.010	0.00	0.25
K	.000	.010	0.00	0.25
L	.779	.842	19.79	21.39
L1	.087	.102	2.21	2.59
Q	.122	.138	3.10	3.51
Q1	.330	.346	8.38	8.79
Q	.240	.256	6.10	6.50
Q1	.330	.346	8.38	8.79
Q	.155	.187	3.94	4.75
Q1	.085	.093	2.16	2.36
S	.243	.253	6.17	6.43

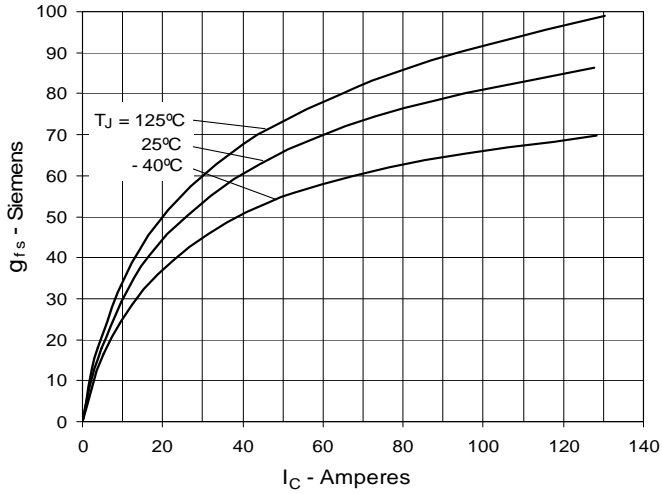
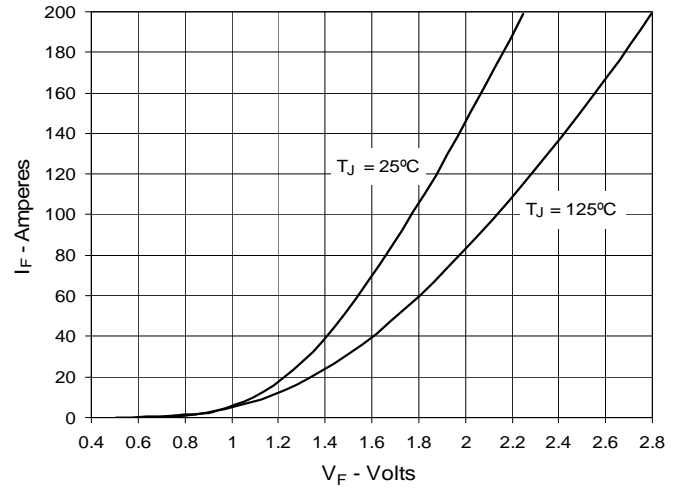
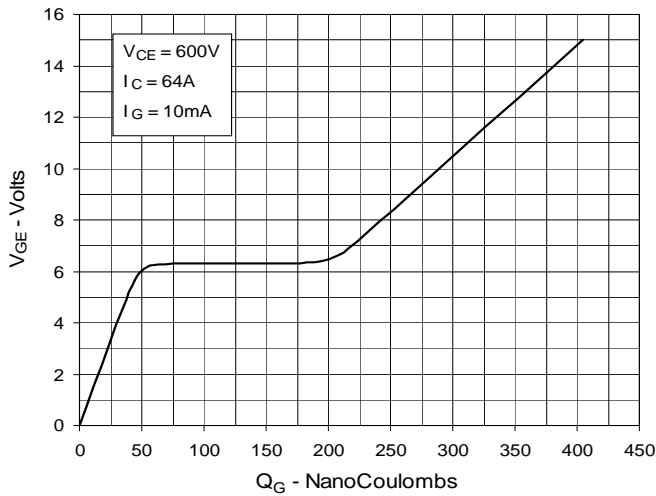
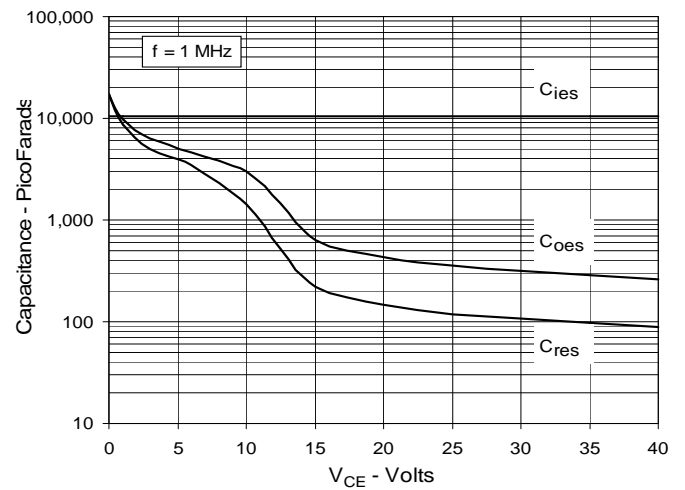
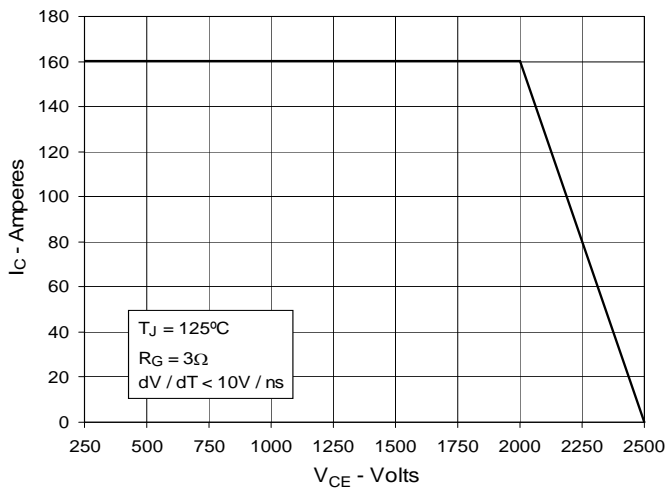
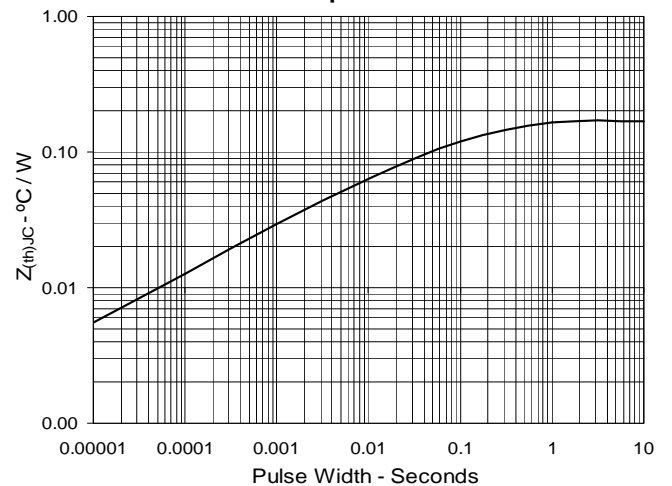
### PLUS 247™ (IXBX) Outline

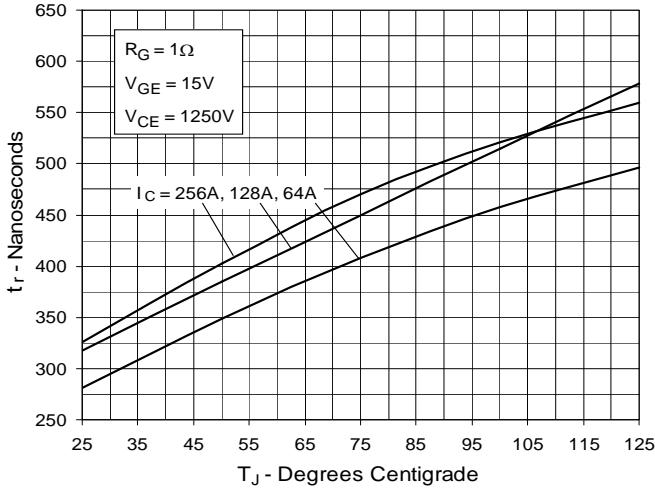
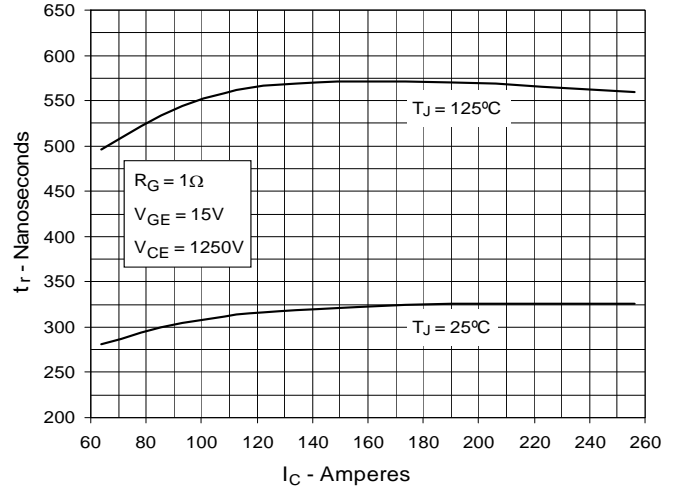
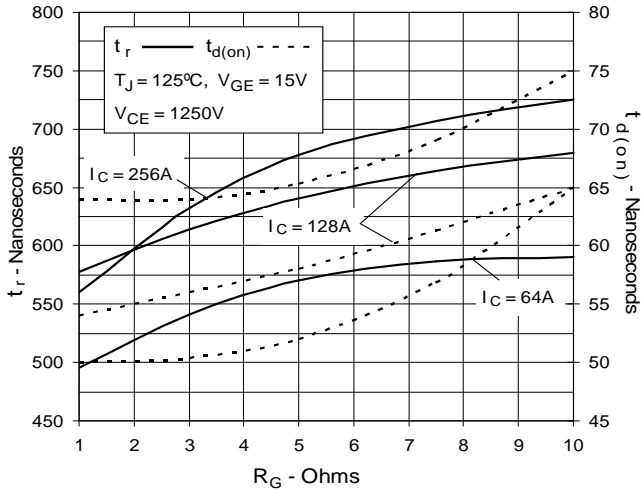
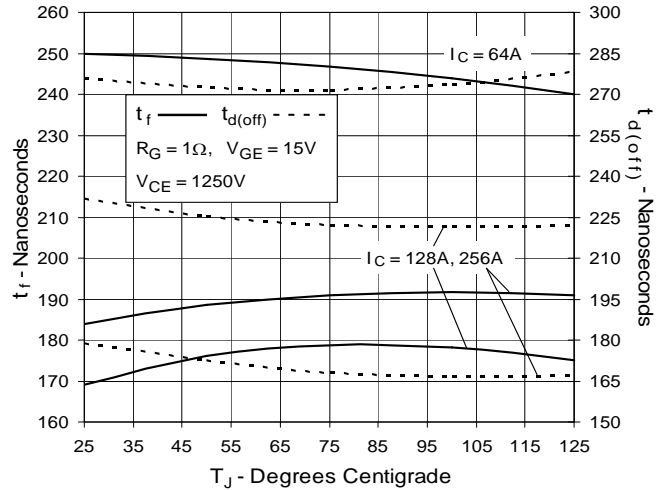
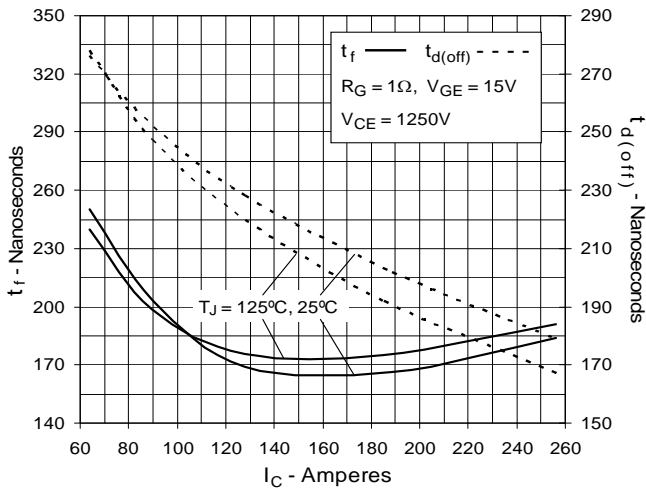


- Terminals: 1 - Gate
- 2 - Drain (Collector)
- 3 - Source (Emitter)

Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	4.83	5.21	.190	.205
A <sub>1</sub>	2.29	2.54	.090	.100
A <sub>2</sub>	1.91	2.16	.075	.085
b	1.14	1.40	.045	.055
b <sub>1</sub>	1.91	2.13	.075	.084
b <sub>2</sub>	2.92	3.12	.115	.123
C	0.61	0.80	.024	.031
D	20.80	21.34	.819	.840
E	15.75	16.13	.620	.635
e	5.45 BSC		.215 BSC	
L	19.81	20.32	.780	.800
L1	3.81	4.32	.150	.170
Q	5.59	6.20	.220	0.244
R	4.32	4.83	.170	.190

**Fig. 1. Output Characteristics @ 25°C**

**Fig. 2. Output Characteristics @ 125°C**

**Fig. 3. Dependence of VCE(sat) on Junction Temperature**

**Fig. 4. Collector-to-Emitter Voltage vs. Gate-to-Emitter Voltage**

**Fig. 5. Breakdown & Threshold Voltages vs. Junction Temperature**

**Fig. 6. Input Admittance**


**Fig. 7. Transconductance**

**Fig. 8. Forward Voltage Drop of Intrinsic Diode**

**Fig. 9. Gate Charge**

**Fig. 10. Capacitance**

**Fig. 11. Reverse-Bias Safe Operating Area**

**Fig. 12. Maximum Transient Thermal Impedance**


**Fig. 13. Resistive Turn-on Rise Time vs. Junction Temperature**

**Fig. 14. Resistive Turn-on Rise Time vs. Drain Current**

**Fig. 15. Resistive Turn-on Switching Times vs. Gate Resistance**

**Fig. 16. Resistive Turn-off Switching Times vs. Junction Temperature**

**Fig. 17. Resistive Turn-off Switching Times vs. Drain Current**

**Fig. 18. Resistive Turn-off Switching Times vs. Gate Resistance**
